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|-----------------------------------|---------------------------------------|--|--|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/575,030 |  | Applicant(s)/Patent Under Reexamination<br>JALALI ET AL. |             |
|                                   | Examiner<br>MARY C. JACOB             |  | Art Unit<br>2123   | Page 1 of 1 |

#### U.S. PATENT DOCUMENTS

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                 | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,920,395                                     | 07-2005         | Brown, George Albert | 702/13         |
| * | B | US-4,520,666                                     | 06-1985         | Coblentz et al.      | 73/152.33      |
| * | C | US-2004/0084180                                  | 05-2004         | Shah et al.          | 166/250.16     |
| * | D | US-5,960,369                                     | 09-1999         | Samaroo, Brian H.    | 702/6          |
| * | E | US-6,082,454                                     | 07-2000         | Tubel, Paulo S.      | 166/250.15     |
|   | F | US-  |                 |                      |                |
|   | G | US-  |                 |                      |                |
|   | H | US-  |                 |                      |                |
|   | I | US-  |                 |                      |                |
|   | J | US-  |                 |                      |                |
|   | K | US-  |                 |                      |                |
|   | L | US-  |                 |                      |                |
|   | M | US-  |                 |                      |                |

#### FOREIGN PATENT DOCUMENTS

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

#### NON-PATENT DOCUMENTS

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |
|---|---|--|
|   | U | Finsterle, Stefan, "iTough2 User's Guide", Earth Sciences Division, Lawrence Berkley National Laboratory, University of California, May 2000                                   |
|   | V | Akin, Srerhat, "Analysis of Tracer Tests with Simple Spreadsheet Models", Computers and Geosciences, 27, pages 171-178, 2001   |
|   | W | Sakaguchi et al, "Temperature Logging by the Distributed Temperature Sensing Technique During Injection Tests", Proceedings, World Geothermal Conference, May 28-June 10, 2000 |
|   | X |  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.